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LETTER TO THE EDITOR

## Observation of a semimetal–semiconductor phase transition in the intermetallic ZrTe<sub>5</sub>

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## Abstract

Temperature dependent high-resolution angle-resolved photoelectron spectroscopy has been performed on the quasi-two-dimensional compound ZrTe<sub>5</sub>, a metal at low temperatures ( $T \leq 4.2$  K) that exhibits a maximum resistivity at a temperature ( $T_c$ ), concomitant with a sign change of the thermopower. A semiconducting gap has been observed in the photoemission spectra, where the valence band maximum shifts upward from 82 meV (75 K) to 40 meV (170 K) as a function of temperature. The band shifts are accompanied by small band distortions. Based on the photoemission experiments, in conjunction with the metallic character of ZrTe<sub>5</sub> at low temperatures, we have modelled the thermopower of ZrTe<sub>5</sub> by treating it as a metal at low temperatures and a semiconductor at elevated temperatures.

Low-dimensional (2D) and quasi-low-dimension materials have received considerable attention due to their tendency to exhibit novel behaviour such as superconductivity [1, 2], colossal magnetoresistance (CMR) [3, 4], and charge density wave (CDW) formation [5–7], to name a few. The aforementioned behaviour is typically accompanied by a metal–nonmetal or semimetal–nonmetal transition associated with either the formation of a gap [1, 2, 4] or changes in the width of the gap [3, 4]. Low-dimensional systems are inherently unstable due to correlation and exchange effects, and consequently they exhibit structural instabilities such as Jahn–Teller distortions [4] or CDW distortions [5–7]. One class of these exotic materials is the pentatellurides (ZrTe<sub>5</sub> and HfTe<sub>5</sub>), which exhibit anomalous transport properties attributed to their quasi-two-dimensional structure [8, 9]. The structure of the pentatellurides consists of zigzag chains of Te atoms along the *a*-axis that link prismatic chains of ZrTe<sub>6</sub> along the

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**Figure 1.** The temperature dependent thermopower (bold curve) and resistivity (thin curve) of  $ZrTe_5$ , where the resistivity has been normalized to  $\rho$  (273 K). The open squares and circles are the fits to the thermopower using equations (2) and (4), respectively.

*c*-axis, which together form 2D planes weakly bonded via van der Waals forces along the *b*-axis. This structure belongs to the *Cmcm* ( $D_{2h}^{17}$ ) space group. Presented in figure 1 is the bulk resistivity and thermopower of ZrTe<sub>5</sub> as a function of temperature. The growth and experimental procedures for measuring the resistivity and thermopower are discussed in detail elsewhere [10]. Summarizing figure 1, the resistivity of ZrTe<sub>5</sub> increases with temperature, consistent with metallic behaviour, until it peaks at  $T \simeq 135$  K, at which point the resistivity begins to decrease, reminiscent of a semiconductor. The room temperature resistivity of ZrTe<sub>5</sub> is of the order 0.7 m $\Omega$  cm [11], which suggests that it is a poor semimetal, at best. This paradoxical behaviour of ZrTe<sub>5</sub> has eluded explanation for nearly 20 years.

Since the mid-1980s it has been hypothesized that the anomalous peaks in the resistivities (figure 1) of this class of materials were signatures of charge density waves. The rationale behind this hypothesis is based, in part, on the similarities between the crystal structures of the pentatellurides and NbSe<sub>3</sub>, a known CDW system that also possesses an anomalous peak in its resistivity. A further suggestion of CDW formation is the change in the sign of the thermopowers of the pentatellurides, i.e. from electron carriers to hole carriers, at a temperature which corresponds to the anomalies in their respective resistivities [11, 12]. However, attempts to observe structural distortions in the pentatellurides to verify the formation of CDWs have been unsuccessful [13]. The only information on the electronic structure of ZrTe<sub>5</sub> has come indirectly from Shubnikov–de Haas (SdH) measurements acquired between 1.3 and 4.2 K [11, 12], which suggested that the valence band structure in the vicinity of the Fermi level consists of three bands, two electron bands and one hole band. The SdH measurements of ZrTe<sub>5</sub> are in reasonable agreement with band structure calculations of ZrTe<sub>5</sub> by Whangbo et al [14]. In order to shed new light on the question of CDW formation in the pentatellurides, we have measured the band structure of  $ZrTe_5$  as a function of temperature using high-resolution angle-resolved photoelectron spectroscopy (APRES).

The angle-resolved photoemission studies were performed at the Synchrotron Radiation Center in Stoughton, WI, on the Ames-Montana beamline using a 50 mm hemispherical analyser and on the 4 m normal incidence monochromator (NIM) using a Scienta SES 200 multichannel analyser. For the sack of brevity, only spectra acquired with the Scienta analyser on the 4 m NIM beamline are presented. The samples were ribbon-like, where the long



**Figure 2.** Intensity maps of the density of states of  $ZrTe_5$  acquired along the  $\Gamma$ -X high symmetry direction for (a) T = 170 K and (b) T = 75 K, and (c) an intensity difference map between the maps in (a) and (b).

(This figure is in colour only in the electronic version)

axis was the Zr chain (*a*) axis. The visual orientation was confirmed by *ex situ* Laue and *in situ* symmetries of the band dispersions. The samples were initially cooled to 20 K, then raised to 170 K and cleaved *in situ* exposing the *a*–*c* plane. The angular resolution of the Scienta analyser is  $\pm 0.25^{\circ}$ , which corresponds to a reciprocal space resolution of  $0.010 \text{ Å}^{-1}$ ; 1.25% of  $\pi/a$  or 4.25% of  $\pi/c$ . Spectra were acquired along the  $\Gamma$ –X (*a*-axis in [11]) and  $\Gamma$ –Z (*c*-axis in [11]) directions, respectively. Photon energy dependence of the ZrTe<sub>5</sub> bands at normal emission indicated dispersion perpendicular to the *a*–*c* plane, which is attributed to the weak bonding along the *b*-axis. From a survey of the photon energy dependence of the ZrTe<sub>5</sub> bands, hv = 22 eV corresponded to being the extreme of the perpendicular dispersion. Consequently, all spectra were acquired at a photon energy of 22 eV, which corresponded to an energy resolution of 20 meV.

Presented in figure 2 are normalized two-dimensional intensity maps of the Fermi surface of ZrTe<sub>5</sub> along the  $\Gamma$ -X high symmetry line at (a) 170 K and (b) 75 K. Figure 2(c) is an intensity difference map between figures 2(a) and (b). The band structure of ZrTe<sub>5</sub> in the vicinity of the Fermi level consists of two downward dispersing bands that are nearly degenerate ( $\Delta E \simeq 40$  meV), consistent with tight binding calculations of ZrTe<sub>5</sub> [14]. At 170 K the valence band maximum (VBM) is at a binding energy of 40 meV, but it shifts downward to 82 meV at 75 K, or  $\Delta_{Gap} = 42$  meV. Equivalent band gaps and band shifts were observed for the  $\Gamma$ -Z high symmetry direction (not shown). Note, the band labelled A in figures 2(a) and (b) is absent from the difference map in figure 2(c), indicating that the binding energy of this band is temperature independent. Based on the SdH measurements [11, 12] and the



**Figure 3.** APRES spectrum of ZrTe<sub>5</sub> acquired at  $\Gamma$  from (a) figure 2(a) for T = 170 K and (b) figure 2(b) for T = 75 K, and the experimental band dispersions of ZrTe<sub>5</sub> for (c) T = 170 K and (d) T = 75 K. In (a) and (b) the symbols are the experimental data, the solid curves are the fits, and the dashed curves are the deconvolutions of the fits into individual bands.

band structure calculations [14] of  $ZrTe_5$ , the spectra in figure 2 have been fitted with two Lorentzians convoluted with Gaussians. Examples of the fits are presented in figures 3(a) and (b). The temperature dependent band dispersions of  $ZrTe_5$ , based on the deconvolutions, are displayed in figures 3(c) and (d), respectively.

The downward dispersion of the ZrTe<sub>5</sub> bands in figures 2 and 3 is consistent with the heavy hole (HH) and the light hole (LH) bands typical of a semiconductor [15], and when taken in conjunction with the persistence of a band gap at 20 K, indicates that ZrTe<sub>5</sub> is a semiconductor for  $T \ge 20$  K, as opposed to a semimetal. On the other hand, since the SdH effect requires Fermi level crossings, ZrTe<sub>5</sub> must be metallic for  $T \le 4.2$  K [11]. Based on the ARPES and SdH measurements, we must conclude that ZrTe<sub>5</sub> exhibits a metal–semiconductor phase transition for 4.2 K < T < 20 K. Furthermore, the APRES and SdH measurements [11, 12], in agreement with the band structure calculations [14], indicate that ZrTe<sub>5</sub> is a direct band gap semiconductor for  $T \ge 20$  K. It is worth noting that the band structure of ZrTe<sub>5</sub> is reminiscent of  $\alpha$ -Sn (zero band gap) and HgTe (negative bandgap) [15].

Whangbo *et al* compared the band structure of a 2D ZrTe<sub>5</sub> slab and 3D ZrTe<sub>5</sub> [14] in order to evaluate the effects of interlayer interactions between a-c planes on the band structure. For the 2D slab, the band structure in the vicinity of the Fermi level consists of two highly dispersive bands, one downward dispersing hole band <u>a</u> (occupied) and one upward dispersing electron band <u>b</u> (unoccupied), respectively, separated by a 50 meV band gap. Consequently, the isolated 2D ZrTe<sub>5</sub> slab is a semiconductor. The <u>a</u>-band originates from the Te 5p<sub>z</sub> orbitals of the prismatic chains in the a-c plane and the <u>b</u>-band originates from the Te 5p<sub>z</sub> orbitals of the zigzag chains in the a-c plane.

For 3D ZrTe<sub>5</sub> Whangbo *et al* found that interplane interactions between the a-c planes causes doubling of the <u>a</u> and <u>b</u> bands. The 3D ZrTe<sub>5</sub> band structure in the vicinity of the Fermi level consists of two downward dispersing bands, a<sub>1</sub> and a<sub>2</sub>, and two upward dispersing band, b<sub>1</sub> and b<sub>2</sub>, respectively. An additional effect of the interplane interactions is the occupation of the b<sub>1</sub> band due to overlap with the a<sub>2</sub> band, i.e. a<sub>2</sub> and b<sub>1</sub> exhibit Fermi level crossings, while a<sub>1</sub> and b<sub>2</sub> do not cross the Fermi level. In contrast to the 2D ZrTe<sub>5</sub> slab, 3D ZrTe<sub>5</sub> is metallic and the metallicity arises from interlayer interactions.

The 3D valence band structure of ZrTe<sub>5</sub> predicted by Whangbo *et al* [14] is in excellent agreement with the ARPES spectra in figures 2 and 3, with the exclusion of the predicted Fermi level crossings. Conversely, the 50 meV band gap predicted for the 2D ZrTe<sub>5</sub> slab is consistent with the minimum gap of 40 meV (170 K) observed with ARPES (figures 2 and 3). In contrast, the SdH measurements indicate a metallic phase for ZrTe<sub>5</sub> for T < 4.2 K, in agreement with the tight binding calculations of 3D ZrTe<sub>5</sub> by Whangbo *et al* [14]. However, the SdH measurements observed three band crossings, as opposed to the two predicted for 3D ZrTe<sub>5</sub> [14]. While the ground state 3D tight binding calculations of ZrTe<sub>5</sub> is flawed, it does capture the basics of ZrTe<sub>5</sub>. Namely, at low temperatures ZrTe<sub>5</sub> is metallic and the valence band structure in the vicinity of the Fermi level consists of two downward dispersing hole-like bands. The significance of the calculations of Whangbo *et al* [14] is that the semimetallic properties of ZrTe<sub>5</sub> for T < 4.2 K arise from interplane interactions as opposed to intraplane interactions at these temperatures are much weaker than those in the ground state calculation of 3D ZrTe<sub>5</sub> for  $T \ge 20$  K indicates that the interplane interactions at these temperatures are much weaker than those in the ground state calculation of 3D ZrTe<sub>5</sub> [14].

Since  $ZrTe_5$  has an even number of electrons per unit cell, at the metal–semiconductor transition it must be an intrinsic semiconductor, i.e. the chemical potential is midgap. The upward shift of the valence band maximum of  $ZrTe_5$  from 82 meV at 75 K to 40 meV at 170 K is consistent with an intrinsic semiconductor. Specifically, the chemical potential for an intrinsic semiconductor will shift downward towards the VBM as a function of temperature, provided the hole effective mass ( $m_h$ ) is less than the electron effective mass ( $m_e$ ) [16]. A ratio of  $m_h/m_e > 1$  is consistent with the positive sign of the thermopower in figure 1 for T > 135 K. The 3D character of the bands of  $ZrTe_5$  precluded us from performing constant initial state experiments and therefore we cannot comment on the role of final state effects on the band structure. However, invoking final state effects to explain the temperature dependent valence band shifts is inconsistent with the bulk transport in figure 1.

If taken alone, the band structure at T > 135 K in figure 2(a) could be argued to be reminiscent of a semimetal. However, the transport data in figure 1 do not support this conclusion. In order to resolve this contradiction the unoccupied density states need to be examined. In the absence and difficulties of acquiring this data, we hypothesize that the upward shift of the occupied bands is accompanied by an equivalent upward shift of the lowest unoccupied band. If this is indeed the case then the presence of occupied states at the chemical potential could not be taken as an indication of a semimetal state since a gap remains, i.e. a semiconducting phase. Consequently, it is concluded that at T > 135 K ZrTe<sub>5</sub> is a p-type semiconductor.

Based on results of the SdH measurements [11] and this photoemission study of  $ZrTe_5$ , we have developed a simple model to explain the temperature dependence of the thermopower in figure 1. Classically, the temperature dependence of the thermopower (*S*) of a metal can be expressed by the Mott–Jones equation:

$$S(T) = -\frac{\pi^2 k_{\rm B}^2 T}{3eE_{\rm FO}}a,\tag{1}$$

where  $k_{\rm B}$  is the Boltzmann constant, *T* is temperature, *e* is the electron charge,  $E_{\rm FO}$  is the Fermi energy at T = 0 K, and *a* is a numerical constant that accounts for changes in electron transport, such as the mean free path of the electron, as a function of electron kinetic energy [16]. Since electron conduction is mediated through scattering by phonons, impurities and crystal defects, *a* should be proportional to the mean free path of the conduction electrons ( $l_s$ ), assuming a simple Drude model of scattering. Therefore, we can rewrite equation (1) as

$$S(T) = -\left[\frac{\pi^2 k_{\rm B}^2 T}{3e E_{\rm FO}}\right] [Cl_{\rm s}],\tag{2}$$

where *C* is a constant with units of reciprocal length. Using equation (2) we have fitted the low temperature regime of the thermopower of  $ZrTe_5$  in figure 1. We see that this simple model begins to fail around 90 K, which we attribute to changes in the density of states at the Fermi level corresponding to the onset of the transition to the semiconducting phase.

In order to model the transport in the semiconducting phase we replace  $l_s$  in equation (2) with  $v_d \tau$ , where  $v_d$  is the drift velocity of a hole and  $\tau$  is the mean free time between collisions. From the hole conductivity ( $\sigma$ ) for a semiconductor we can extract  $\tau$ :

$$\tau_{\rm h} = \left[\frac{m_{\rm h}^* \sigma(T)}{e^2 N}\right] \left[\alpha e^{\frac{E_{\rm g}}{2k_{\rm B}T}} + e^{-\frac{E_{\rm g}}{2k_{\rm B}T}}\right]^{-1},\tag{3}$$

where  $m_h^*$  is the hole effective mass,  $\sigma(T)$  is the temperature dependent conductivity, N is the hole concentration, which we have assumed does not change with temperature,  $\alpha$  is the ratio of the electron mobility to the hole mobility, and  $E_g$  is the energy gap of the semiconductor. Within a first approximation, we assume that  $\sigma(T) = aT$ , which from examination of figure 1 we see is reasonable for 135 K < T < 170 K. Upon making this substitution into equation (2) we arrive at the following relationship for the thermopower:

$$S(T) = -\left[C\frac{\pi^2 m_{\rm h}^* k_{\rm B}^2 v_{\rm d} a T^2}{3e^3 N E_{\rm FO}}\right] \left[\alpha e^{\frac{E_{\rm g}}{2k_{\rm B}T}} + e^{-\frac{E_{\rm g}}{2k_{\rm B}T}}\right]^{-1} = -DT^2 \left[\alpha e^{\frac{E_{\rm g}}{2k_{\rm B}T}} + e^{-\frac{E_{\rm g}}{2k_{\rm B}T}}\right]^{-1},$$
(4)

where  $D = \left[C \frac{\pi^2 m_h^k k_B^2 v_d a}{3e^3 N E_{FO}}\right]$ . The linear region of the thermopower (135 K < T < 170 K) in figure 1 was fitted with equation (4) and then calculated for 75 K < T < 320 K, where D,  $\alpha$  and  $E_g$  were the free parameters. From examination of figure 1 we see that a surprisingly good fit of the thermopower is achieved for T > 120 K. We attribute the failure of this model at T < 120 K to temperature dependent changes in phonon scattering and the phase transition to the metallic phase. The theoretical gap for the semiconducting phase of ZrTe<sub>5</sub> based on the fit is 108 meV, which only differs, approximately, by a factor of two from the minimum band gap of 40 meV, as determined by ARPES, and the theoretical gap of 50 meV for the 2D  $ZrTe_5$  slab [14].

In conclusion, we have used the technique of high-resolution angle-resolved photoelectron spectroscopy to study the temperature dependent electronic structure of ZrTe<sub>5</sub>. In the temperature range 20 K  $\leq T \leq$  170 K a band gap was observed, indicative of a semiconducting phase. In addition, the chemical potential was observed to shift downwards with temperature, consistent with an intrinsic semiconductor. Since ZrTe<sub>5</sub> is metallic for  $T \leq 4.5$  K, as determined from the Shubnikov–de Haas effect, we have concluded that a metal–semiconductor phase transition occurs for 4.2 K < T < 20 K. While we cannot exclude charge density wave formation for T < 20 K, the lack of experimental evidence argues against this explanation for the metal–semiconductor transition. However, our observations suggest that it is a reduction in interplane interactions between the a-c planes of ZrTe<sub>5</sub> that is responsible for the transition. A thorough study of the temperature dependent phonon density of states would likely shed much needed light on the origin of the phase transition.

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